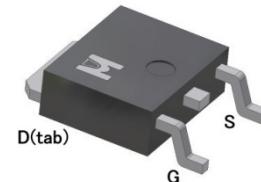
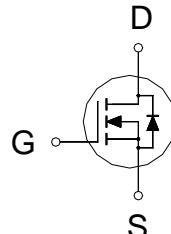


N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV_{DSS}	30V
$R_{DS(on)}$ (MAX.)	4.0m Ω
I_D	90A



UIS, Rg 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS ($T_c = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS		UNIT
		10s	Steady State	
Gate-Source Voltage	V_{GS}	± 20		V
Continuous Drain Current	I_D	90		A
		55		
Continuous Drain Current	I_D	28	17	
		22	13	
Pulsed Drain Current ¹	I_{DM}	180		
Avalanche Current	I_{AS}	53		
Avalanche Energy	E_{AS}	140		mJ
Repetitive Avalanche Energy ²	E_{AR}	40		
Power Dissipation	P_D	83		W
		41		
Power Dissipation	P_D	6.5	2.5	W
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 175		°C

100% UIS testing in condition of $V_D=15V$, $L=0.1mH$, $V_G=10V$, $I_L=40A$, Rated $V_{DS}=30V$ N-CH

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	$R_{\theta JC}$		1.8	°C / W
Junction-to-Ambient ³ ($t \leq 10s$)	$R_{\theta JA}$		23	
Junction-to-Ambient ³	$R_{\theta JA}$		60	

¹Pulse width limited by maximum junction temperature.

²Duty cycle $\leq 1\%$

³When mounted on a 1 in² pad of 2 oz copper.

ELECTRICAL CHARACTERISTICS ($T_c = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	30			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.0	1.6	3.0	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 24V, V_{GS} = 0V$			1	μA
		$V_{DS} = 20V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			25	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = 10V, V_{GS} = 10V$	90			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 10V, I_D = 30A$		3.2	4.0	$\text{m}\Omega$
		$V_{GS} = 4.5V, I_D = 24A$		4.9	6.6	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 24A$		25		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1\text{MHz}$		3435		pF
Output Capacitance	C_{oss}			485		
Reverse Transfer Capacitance	C_{rss}			457		
Gate Resistance	R_g	$V_{GS} = 15\text{mV}, V_{DS} = 0V, f = 1\text{MHz}$		1.2		Ω
Total Gate Charge ^{1,2}	$Q_g(V_{GS}=10V)$	$V_{DS} = 15V, V_{GS} = 10V,$ $I_D = 30A$		59		nC
	$Q_g(V_{GS}=4.5V)$			32		
Gate-Source Charge ^{1,2}	Q_{gs}			6.9		
Gate-Drain Charge ^{1,2}	Q_{gd}			16		
Turn-On Delay Time ^{1,2}	$t_{d(\text{on})}$	$V_{DS} = 15V,$ $I_D = 24A, V_{GS} = 10V, R_{GS} = 2.7\Omega$		20		nS
Rise Time ^{1,2}	t_r			20		
Turn-Off Delay Time ^{1,2}	$t_{d(\text{off})}$			60		
Fall Time ^{1,2}	t_f			25		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_c = 25^\circ\text{C}$)						
Continuous Current	I_S	$I_F = I_S, V_{GS} = 0V$			90	A
Pulsed Current ³	I_{SM}				180	
Forward Voltage ¹	V_{SD}				1.3	V
Reverse Recovery Time	t_{rr}			35		nS
Peak Reverse Recovery Current	$I_{RM(\text{REC})}$			200		A
Reverse Recovery Charge	Q_{rr}			30		nC

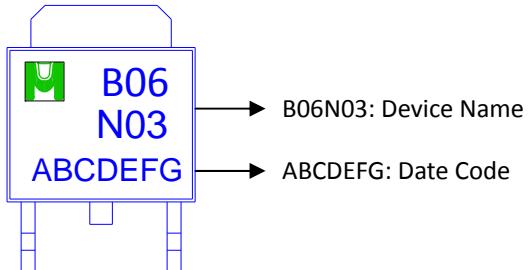
¹Pulse test : Pulse Width \leq 300 μ sec, Duty Cycle \leq 2%.

²Independent of operating temperature.

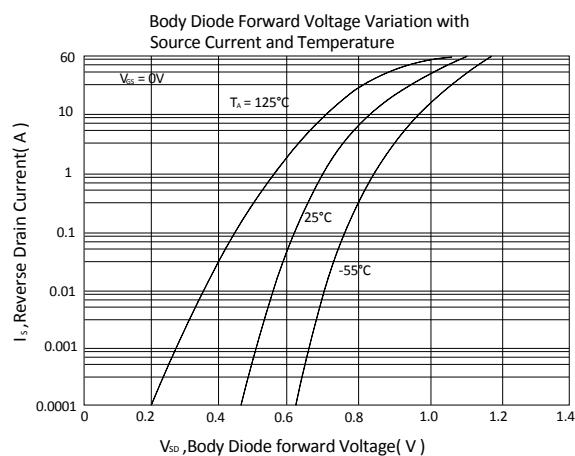
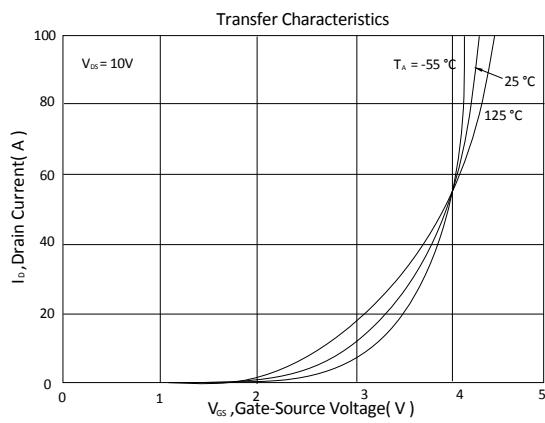
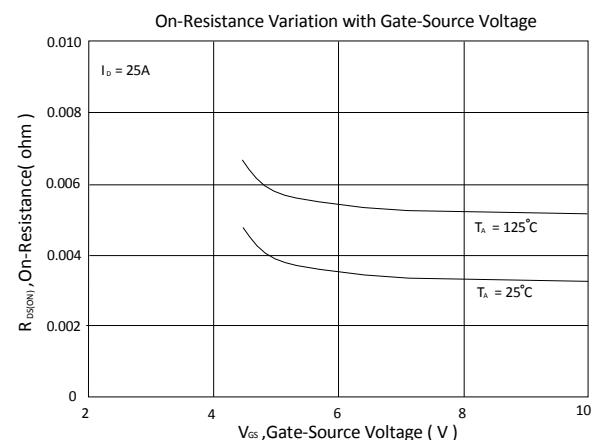
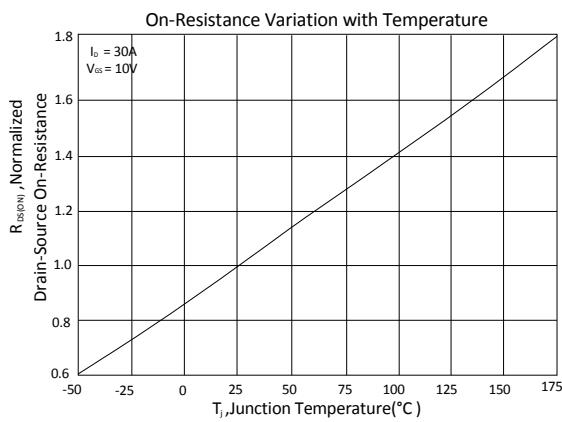
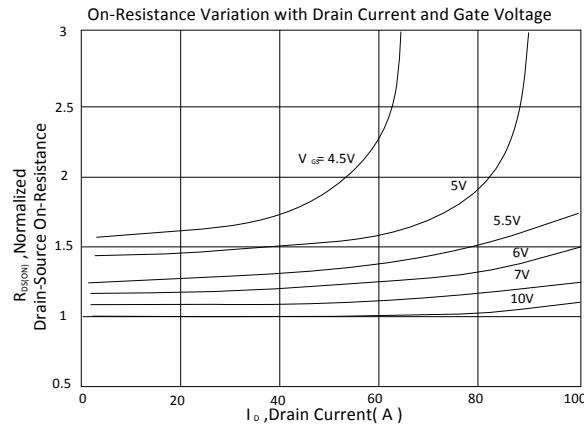
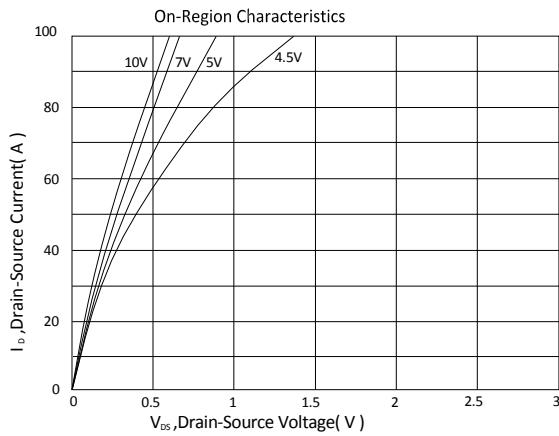
³Pulse width limited by maximum junction temperature.

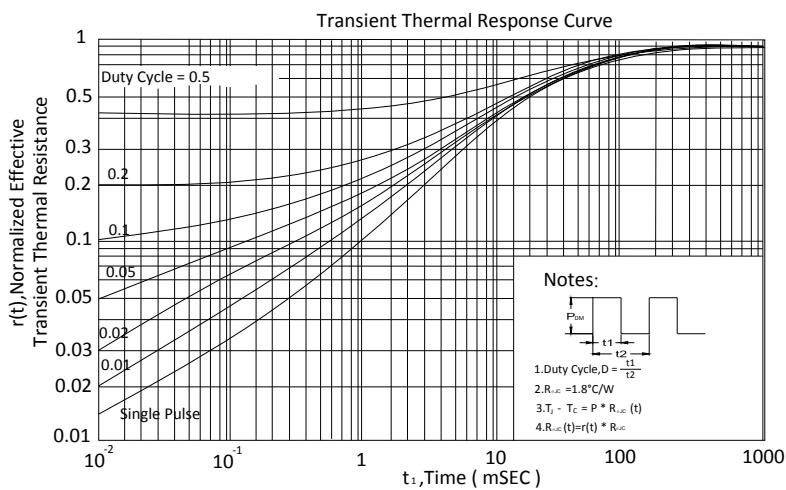
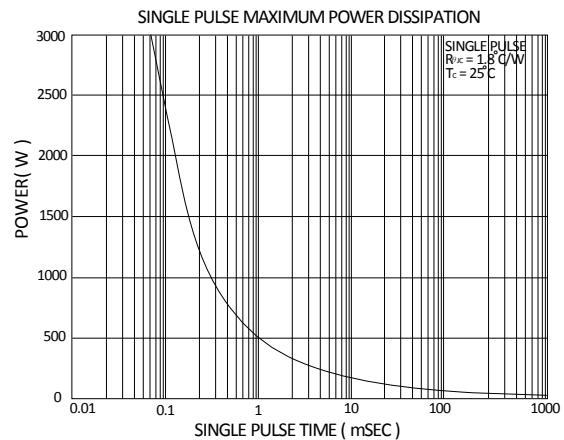
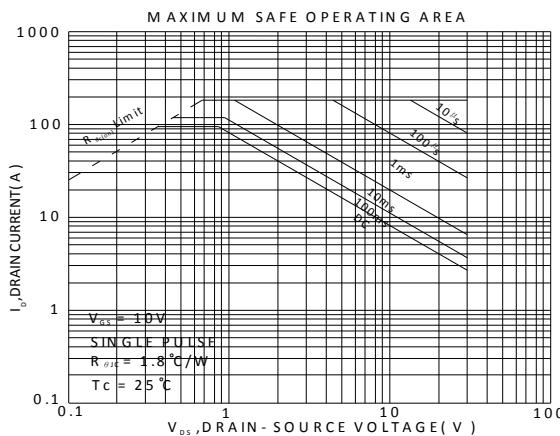
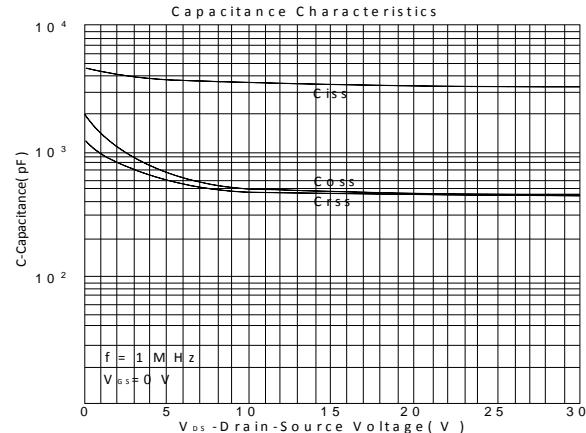
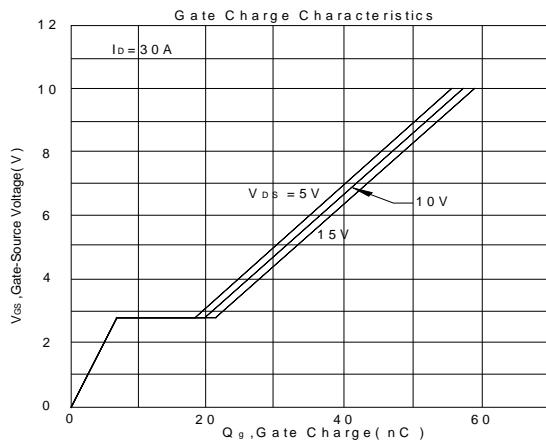
Ordering & Marking Information:

Device Name: EMB06N03AN for DPAK (TO-252)



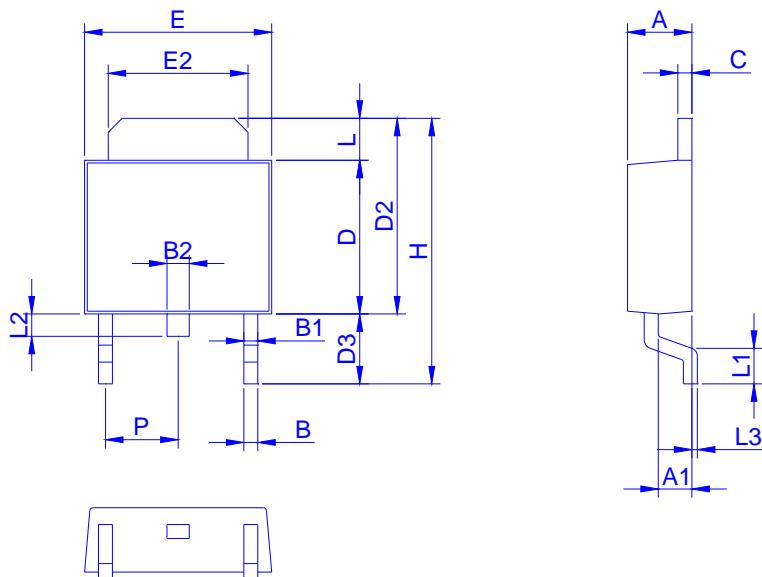
TYPICAL CHARACTERISTICS







Outline Drawing



Dimension	A	A1	B	B1	B2	C	D	D2	D3	E	E2	H	L	L1	L2	L3	P
Min.	2.10	0.95	0.30	0.40	0.60	0.40	5.30	6.70	2.20	6.40	4.80	9.20	0.89	0.90	0.50	0.00	2.10
Max.	2.50	1.30	0.85	0.94	1.00	0.60	6.20	7.30	3.00	6.70	5.45	10.15	1.70	1.65	1.10	0.30	2.50

Footprint

